

Search Notes

Application/Control No.

10/605,517

Examiner

Jean W. Désir

Applicant(s)/Patent under
Reexamination

LIEN, CHI-CHIN

Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner
348	452 448 451	8/17/2007	JWD
	441, 715		
	911		
	430.1		
	431.1		
375	240.01		
	240.26		
382	236, 233		
Updated	Search	1/30/2008	JWD

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
348	452	1/30/2008	JWD
	430.1		
	715		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	8/17/2007	JWD
Interference search	1/30/2008	